

Notice of References Cited	Application/Control No. 10/642,542	Applicant(s)/Patent Under Reexamination ISHII ET AL.	
	Examiner Jianchun Qin	Art Unit 2837	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0131717	07-2003	Shiia, Yoshihiro	84/610
	B	US-2003/0177890	09-2003	Furukawa, Rei	84/610
	C	US-2003/0172798	09-2003	Fujiwara et al.	84/609
	D	US-2003/0101862	06-2003	Furukawa, Rei	84/610
	E	US-2002/0178898	12-2002	Hagiwara et al.	84/664
	F	US-2003/0133700	07-2003	Uehara, Haruki	386/96
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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